

INFORMATION DISCLOSURE  
CITATION

ATTY. DOCKET NO.

4105-17

APPLICANT

ONOE et al.

FILING DATE

July 9, 2003

SERIAL NO.

10/615,403

TC/A.U.

2627



(Use several sheets if necessary)

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL /KB/	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	2007/0014047	01/2007	Cho et al.			
	2006/0219655	11/2006	Cho et al.			
	2006/0245312	11/2006	Maeda et al.			
	2006/0182004	08/2006	Maeda et al.			
	2004/0263185	12/2004	Cho et al.	324	636	
	2004/0114913	06/2004	Kume	386	125	
	2003/0053400	03/2003	Cho et al.	369	126	
	2004/0027935	02/2004	Cho et al.	369	126	
	2003/0021213	01/2003	Hagiwara, Yoshiaki	369	101	
	2,872,529	02/1959	Hollmann et al.			
	4,320,491	03/1982	Rustman, James C.	369	126	
	4,455,638	06/1984	Wilson	369	126	
	4,489,278	12/1984	Sawazaki, Norikazu	324	457	
	5,418,029	05/1995	Yamamoto et al.	428	64.2	
	5,481,527	01/1996	Kasanuki et al.	369	126	
	5,646,932	07/1997	Kuribayashi et al.	369	126	
	5,751,685	05/1998	Yi, You-Wen	369	126	
	5,777,977	07/1998	Fujiwara et al.	369	126	
	5,581,537	12/1996	Yamano et al.	369	126	
	5,914,920	06/1999	Yokogawa	369	275.3	
	5,946,284	08/1999	Chung et al.	369	126	
	6,477,132	11/2002	Azuma et al.	369	126	
	6,510,130	01/2003	Hayashi et al.	369	275.3	
	6,515,957	02/2003	Newns et al.	369	126	
	6,653,630	11/2003	Rosenman et al.	250	306	
	6,762,402	07/2004	Choi et al.	250	234	
	6,841,220	01/2005	Onoe et al.	428	66.7	
	6,912,193	06/2005	Cho et al.	369	126	
	6,965,545	11/2005	Hino et al.	369	13.54	
	7,065,033	06/2006	Onoe et al.	369	126	
/KB/	7,149,180	12/2006	Onoe et al.	369	276	

## FOREIGN PATENT DOCUMENTS

DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
/KB/	2003085969	03/2003	JP		ABSTRACT
/KB/	08-075806	03/1996	JP		ABSTRACT
/KB/	644 426 A	10/1950	GB		
/KB/	10-334525	12/1998	JP		ABSTRACT
/KB/	56-107338	08/1981	JP		ABSTRACT

\*Examiner

/Kevin Bernatz/

Date Considered

06/06/2008

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application.

INFORMATION DISCLOSURE  
CITATION

ATTY. DOCKET NO.

SERIAL NO.

4105-17

10/615,403

APPLICANT

ONOE et al.

(Use several sheets if necessary)

FILING DATE

TC/A.U.

July 9, 2003

2627

## OTHER DOCUMENTS (including Author, Title, Date, Pertinent pages, etc.)

62th Japan Society of Applied Physics Lecture Meeting (2001.9 Aichi Institute of Technology) 12p-ZR-2.

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/KB/	5,488,602	01/1996	Yamano et al.	369	126	
	5,808,977	09/1998	Koyanagi et al.	369	127	
	6,001,519	12/1999	Yang et al.			
	6,096,434	08/2000	Yano et al.			
	6,197,989	03/2001	Furukawa et al.	556	450	
	6,942,914	09/2005	Onoe et al.			
	7,212,484	05/2007	Maeda et al.			
	7,242,661	07/2007	Cho et al.			
	7,227,830	6/2007	Cho et al.			
	7,221,639	05/2007	Onoe et al.			
	7,218,600	05/2007	Cho et al.			
	7,151,739	12/2006	Cho et al.			
	2005/0122886	06/2005	Takahashi et al.	369	126	
	2005/0099895	05/2005	Maeda et al.	369	13.01	
	2005/0098532	05/2005	Onoe et al.	216	22	
	20050047288	03/2005	Maeda et al.	369	53.25	
	2004/0252621	12/2004	Cho et al.	369	126	
	2004/0105380	06/2004	Cho et al.	369	126	
	2004/0105373	06/2004	Maeda et al.	369	101	
	2004/0090903	05/2004	Cho et al.	369	126	
	2004/0042351	03/2004	Onoe et al.	369	13.01	
	2002/0131669	09/2002	Onoe et al.	385	14	
	2002/0118906	08/2002	Onoe	385	14	
	2002/0105249	08/2002	Yoshida et al.	310	311	
/KB/	2003/0186090	10/2003	Onoe et al.			

## FOREIGN PATENT DOCUMENTS

						TRANSLATION	
	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	YES	NO
/KB/	1 484 256	09/1977	GB				
/KB/	0 739 004	11/1996	EP				
/KB/	1 154 422	11/2001	EP				

\*Examiner

/Kevin Bernatz/

Date Considered

06/06/2008

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application.

**INFORMATION DISCLOSURE  
CITATION**

ATTY. DOCKET NO.

SERIAL NO.

4105-17

10/615,403

APPLICANT

ONOE et al.

(Use several sheets if necessary)

FILING DATE

TC/A.U.

July 9, 2003

2627

**OTHER DOCUMENTS (including Author, Title, Date, Pertinent pages, etc.)**

/KB/	Kazuta et al, "Determination of crystal polarities of piezoelectric thin film using scanning nonlinear dielectric microscopy", Journal of European Ceramic Society 21 (2001) 1581-1584.
/KB/	The Institution of Electrical Engineers, Stevenage, GB; 1 June 2002; Hiranaga et al, "Nano-sized inverted domain formation in stoichiometric LiTaO <sub>3</sub> /single crystal using Scanning Nonlinear Dielectric Microscopy", XP002292217.
/KB/	Cho et al, "Scanning nonlinear dielectric microscopy with nanometer resolution", Journal of European Ceramic Society 21 (2001) 2131-2134.
/KB/	Cho et al., "Nano domain engineering using scanning nonlinear dielectric microscopy, October 29, 2001, IEE-NANO 2001, pages 352-357.

\*Examiner

/Kevin Bernatz/

Date Considered

06/06/2008

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application.

(Use several sheets if necessary)

**Serial No.**

**10/615.403**

ONOE, A. et

Filing Date

TC/A.U.

**July 9, 2003**

2627

[illegible]

ORIGINAL DOCUMENT						TRANSLATION	
	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	YES	NO
/KB/	57200956	12/1982	JP			ABSTRACT	
/KB/	01/97385 A	12/2001	WO				
/KB/	07334940	12/1995	JP			ABSTRACT	
/KB/	00/36608	6/2000	WO				
/KB/	1 385 161	1/2004	EP				
/KB/	9-511863	11/1997	JP			ABSTRACT	
/KB/	11-176033	7/1999	JP			ABSTRACT	
/KB/	0 480 183	4/1992	EP				
/KB/	9-222430	8/1997	JP			ABSTRACT	
/KB/	59-22250	2/1984	JP			ABSTRACT	

/KB/	Cho et al, "Tbit/inch <sup>2</sup> ferroelectric data storage based on scanning nonlinear dielectric microscopy", Applied Physics Letters, Vol. 81, No. 23, December 2, 2002, pages 4401-4403.

06/06/2008

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application.